

Notice of References Cited

Application/Control No.

10/551,758

Applicant(s)/Patent Under

Reexamination

YOSHII ET AL.

Examiner

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Art Unit

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-4,728,386 A	03-1988	Horvath, Steven C.	156/361
*	B US-5,571,766 A	11-1996	Imai et al.	503/227
*	C US-2002/0024287 A1	02-2002	Miura et al.	313/422
*	D US-6,833,663 B2	12-2004	Tanaka et al.	313/473
*	E US-6,841,926 B2	01-2005	Ito et al.	313/473
*	F US-7,179,572 B2	02-2007	Ohno et al.	430/23
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	WO-01/57905 A1	08-2001	World-PCT	Ito et al.	H01J 9/22
O	WO-02/099831 A1	12-2002	World-PCT	Ohno et al.	H01J 9/227
P	WO-02/37522 A1	05-2002	World-PCT	Tanaka et al.	H01J 29/28
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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